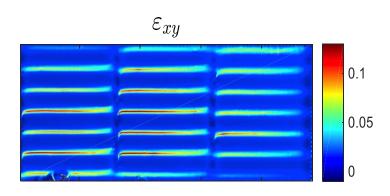
Measuring in-plane displacement and strain fields with the grid method. A feasibility study on superconducting magnet

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Objective:

- measuring displacement and strain fields on a superconducting magnet specimen subjected to a mechanical loading
- applying a suitable full-field measurement technique: the grid method
- are the heterogeneities due to the heterogeneous nature of the material observable?

Outline:

- 1- Basics on the grid method
- 2- Preparation of the specimen
- 3- How to extract displacement/strain fields from the images?
- 4- Results
- 5- Conclusion

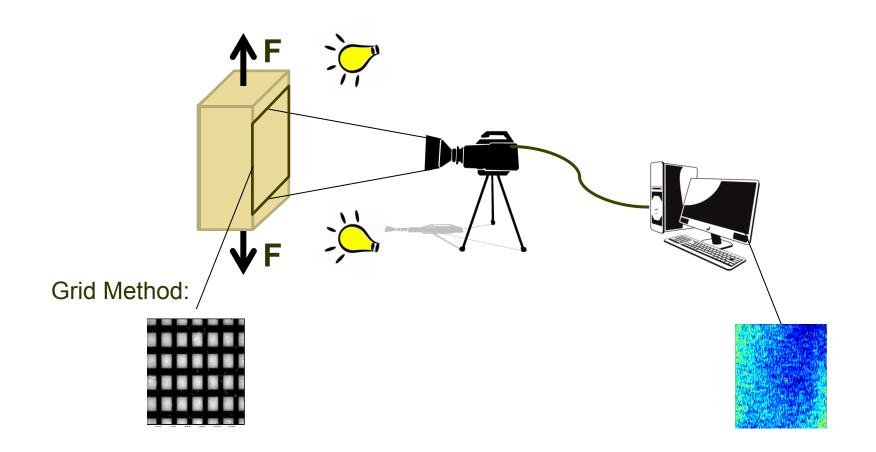
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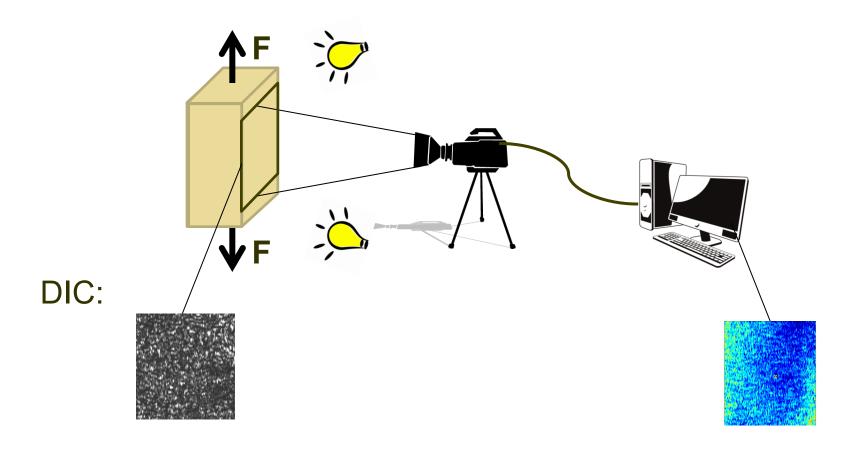
1- Grid bonded/engraved/transferred on the specimen

- 2- Image of the grid captured by a camera before and after loading
- 3- Displacement and strain fields deduced by processing these images



1- Speckle deposited on the specimen

- 2- Image of the speckled pattern captured by a camera before and after loading
- 3- Displacement and strain fields deduced by processing these images



- a	ı pri	ori kı	nowle	edge	on	the	patter	n with	n grid	$l \rightarrow k$	oetter	com	prom	nise	betwe	en
no	ise	level	and	spat	ial r	eso	lution	with	grids	thar	n with	spec	kles	[1]		

- price to pay: depositing a regular marking

Outline

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Step 1:

- cutting the specimen in a superconducting magnet
- polishing the surface of the specimen

Specimen:

- selected and thoroughly polished and prepared by François NUNIO, CEA Paris-Saclay, France
 - cable from JLab magnet for CLS12 torus magnet

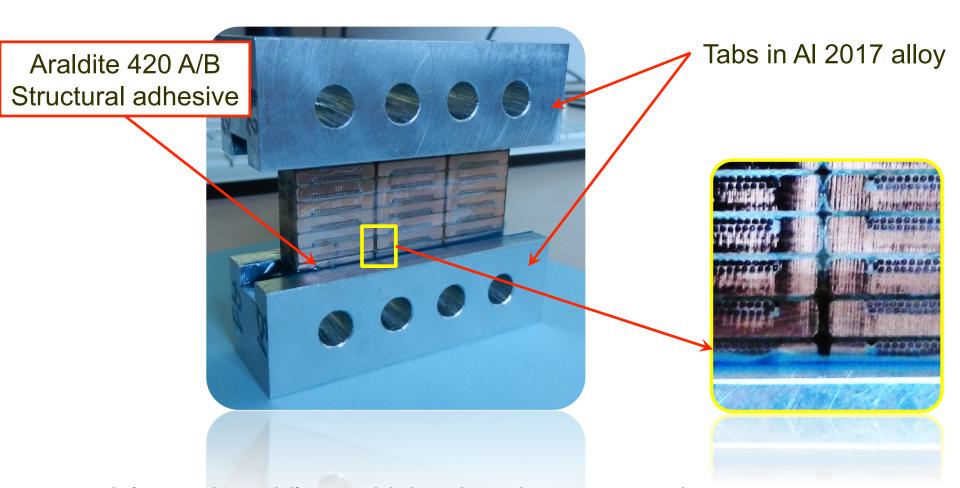




dimensions: 60x35x10 mm³

Step 2:

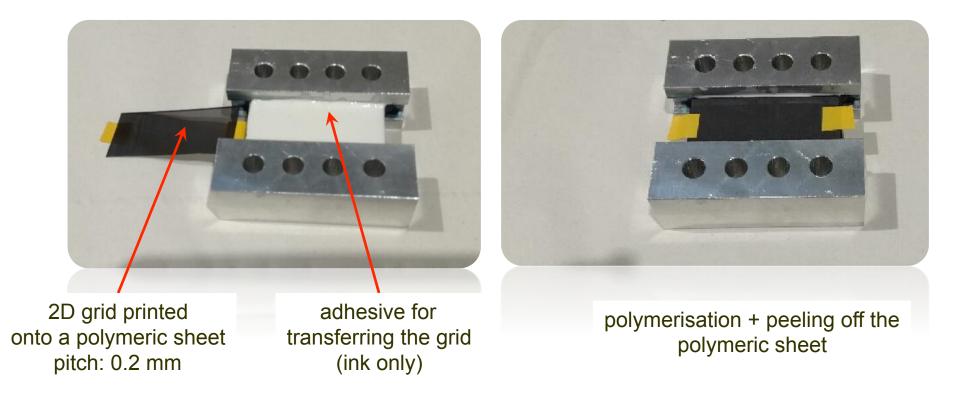
- bonding tabs onto the specimen, suitable for an ARCAN fixture



- special attention while machining the tabs to ensure the symmetry of the resulting specimen
 - adjusting the thickness of the glue (200 mm) with slip gauges
 - polymerisation: 5 hours, 80°C

Step 3:

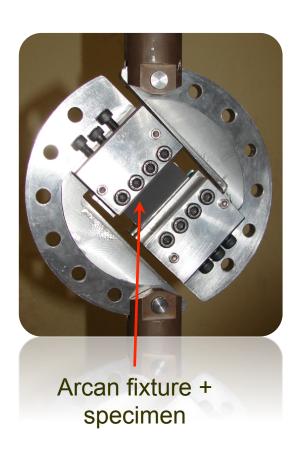
- transferring a 2D grid onto the specimen



- grid printed on the polymeric sheet with a high-resolution photoplotter (64,000 dpi)
 - white epoxy adhesive to ensure a good visual contrast with black inck

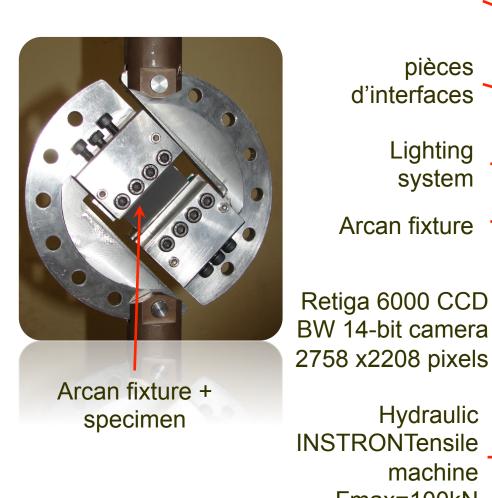
Step 4:

- mounting the specimen in an Arcan fixture + testing it

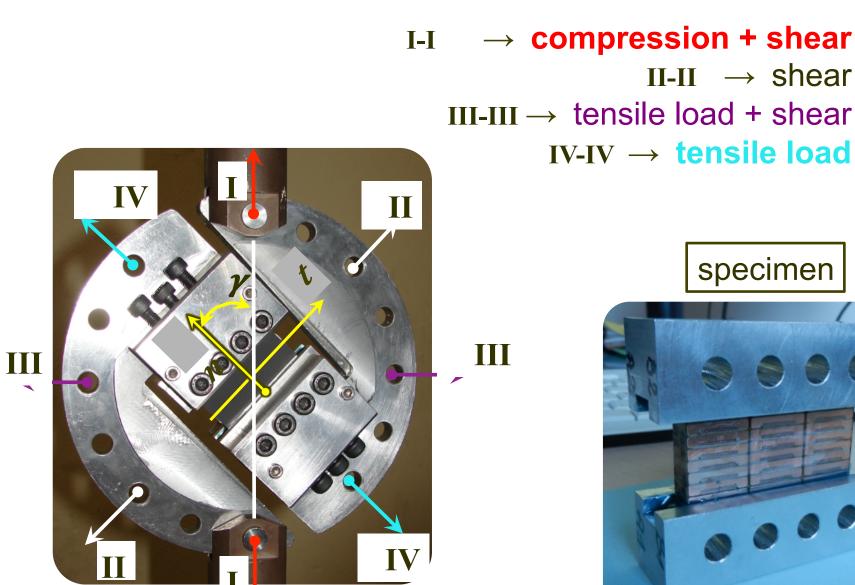


Step 4:

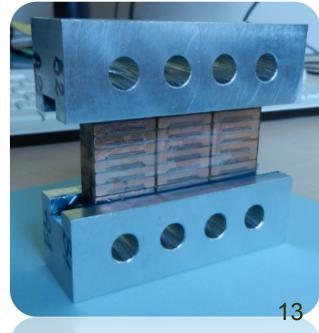
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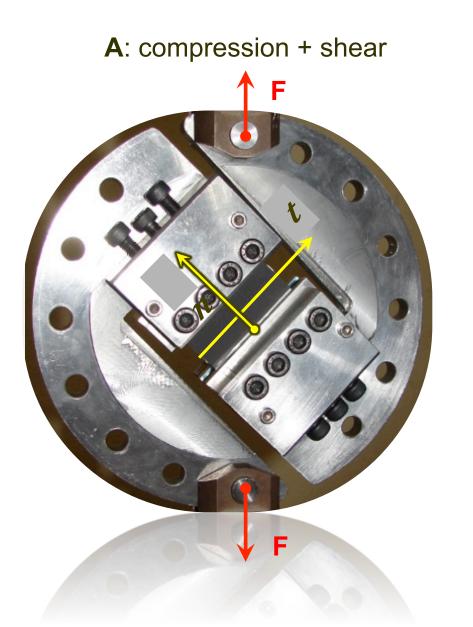
force cell INSTRON Fmax=100kN

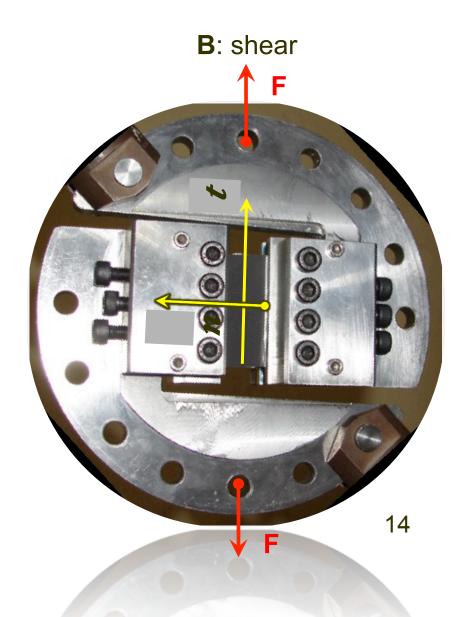


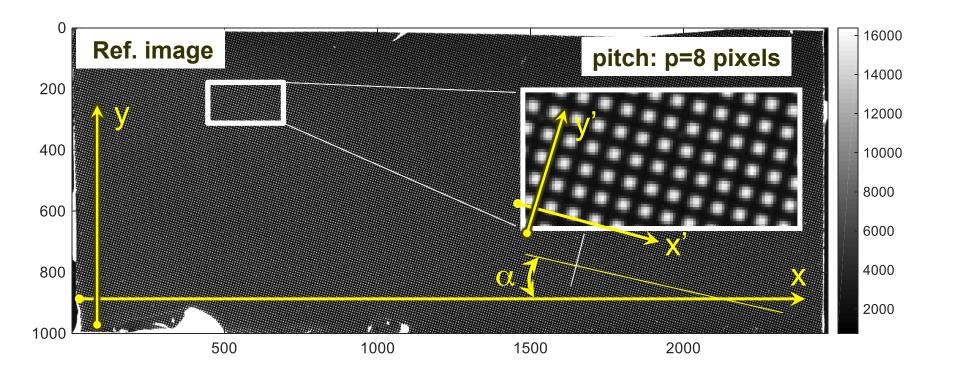
specimen

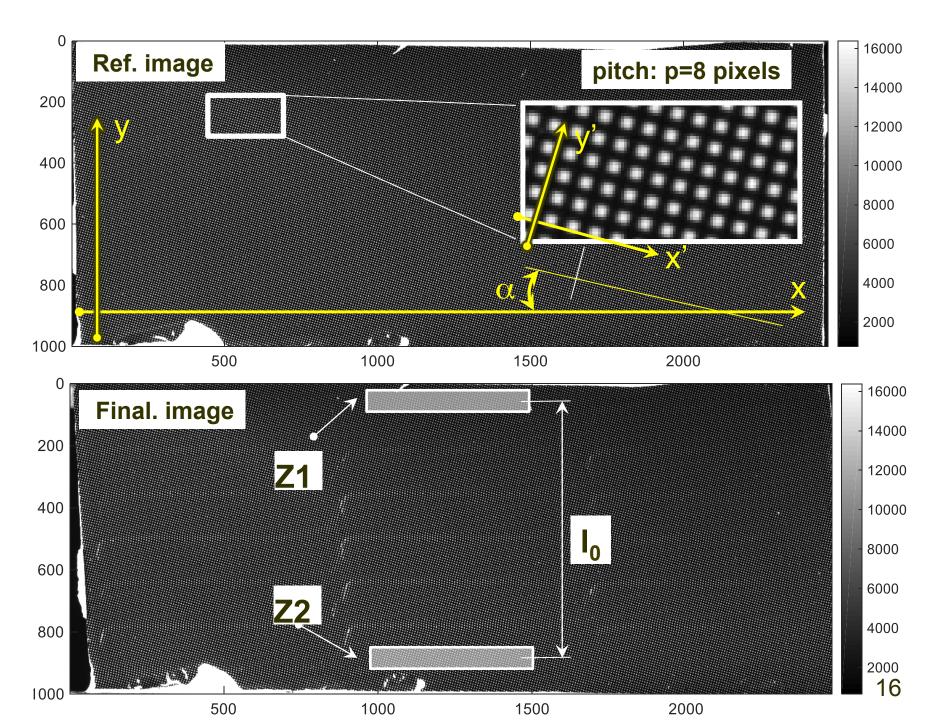


Tested configurations





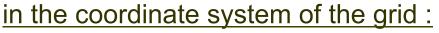


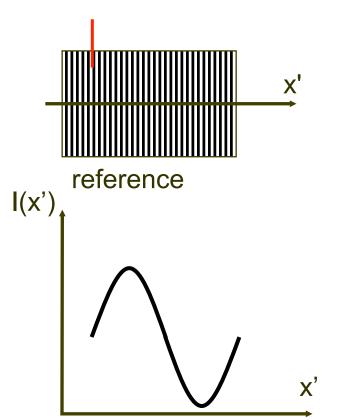


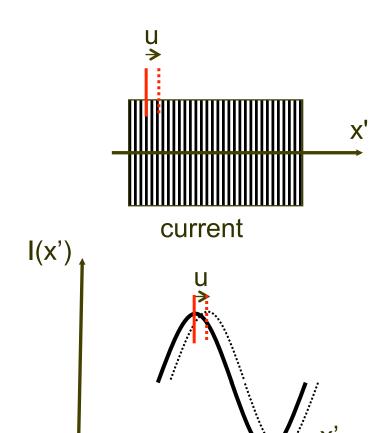
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Link between displacement and phase [1]:





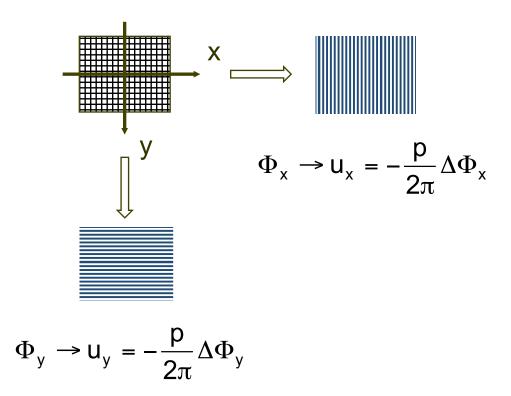


Displacement proportional to the change in phase

$$\rightarrow u = -\frac{p}{2\pi} (\Phi_{current} - \Phi_{reference}) = -\frac{p}{2\pi} \Delta \Phi$$

Case of 2D-grids:

2D grids \rightarrow 2 displacements u_x and u_y



Extracting the phases from the images

- by using a Fourier-based method such as:
 - the Geometric Phase Analysis [1] (the whole spectrum)
 - the windowed Geometric Phase Analysis [2] (windows in the spectrum)
 - the Localized Spectrum Analysis, LSA [3] (points in the spectrum)
- LSA:

$$\widehat{s}(x,y,f,0,\alpha) = \int_{-\infty}^{+\infty} \int_{-\infty}^{+\infty} \underline{s(u,v)} \underline{g(x-u,y-v)} e^{-2i\pi f u(\cos\alpha + f v \sin\alpha)} du dv$$

with:

- 1. s(u,v): signal = matrix of gray levels
- 2. g(x-u,y-v): Gaussian window

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with:

- 1. s(u,v): signal = matrix of gray levels
- 2. g(x-u,y-v): Gaussian window
- $\widehat{s}(x,y,f,0,\alpha)$ and $\widehat{s}(x,y,0,f,\alpha)$: two complex numbers for each image \rightarrow 2 arguments \rightarrow 2 phases for each image \rightarrow 2 displacement components

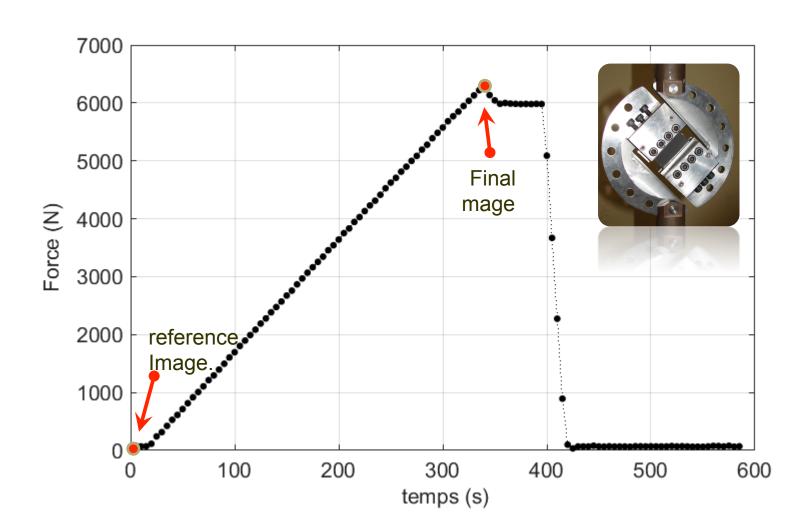
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Test A: compression + shear

- force-driven: 0,02 kN/s, Fmax=6,3 kN (...)

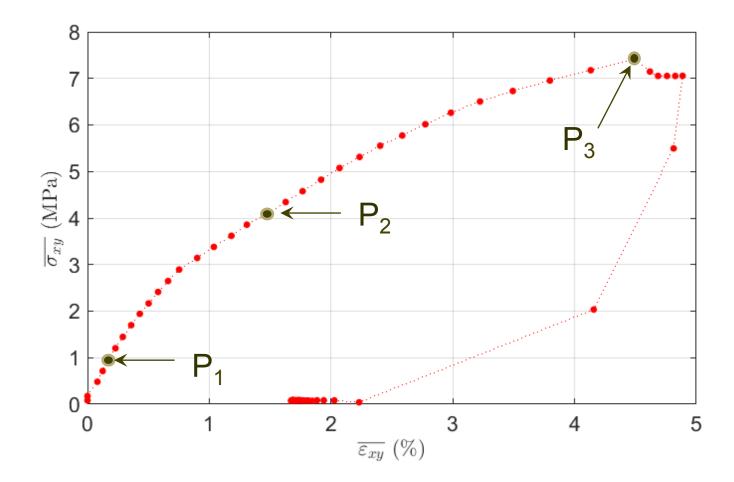
- frequency: 2 images/s



mean stress $\overline{\sigma_{xy}}$ vs. mean strain $\overline{\varepsilon_{xy}}$

$$\overline{\sigma_{xy}} = \frac{F}{S} \times \frac{\sqrt{2}}{2}$$

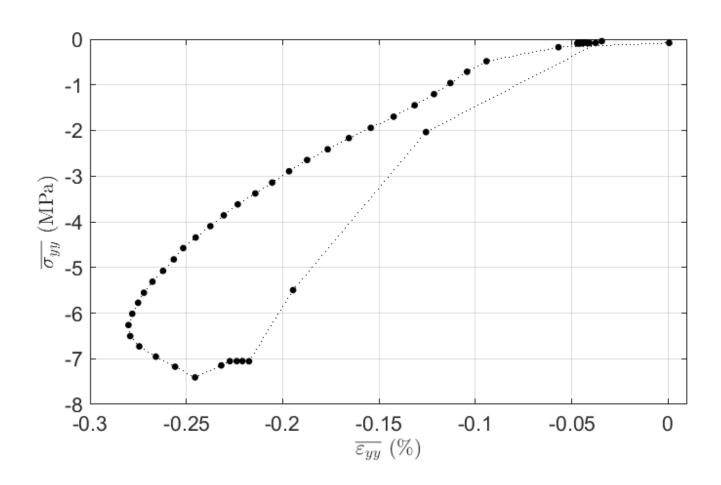
$$\overline{\varepsilon_{xy}} = \frac{\overline{u_x}(Z_1) - \overline{u_x}(Z_2)}{distance(Z_1, Z_2)}$$



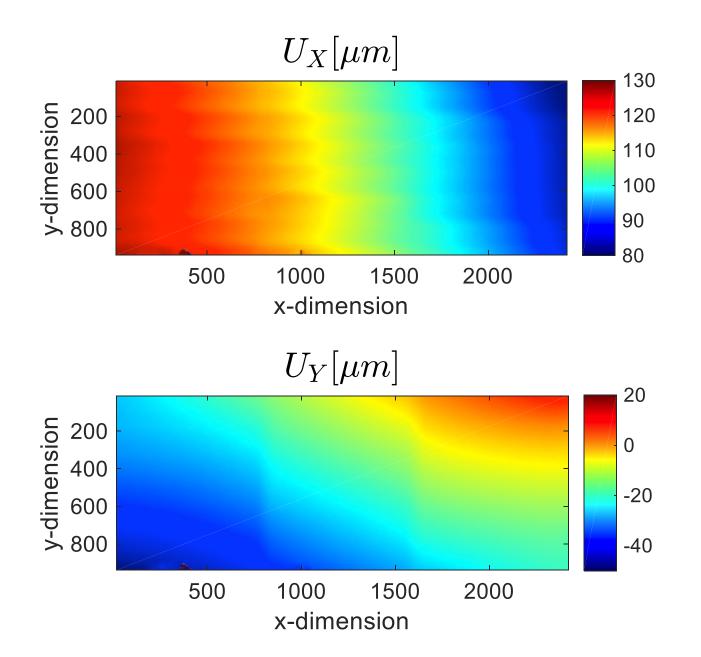
mean stress $\overline{\sigma_{yy}}$ vs. mean strain $\overline{\varepsilon_{yy}}$

$$\overline{\sigma_{yy}} = \frac{F}{S} \times \frac{\sqrt{2}}{2}$$

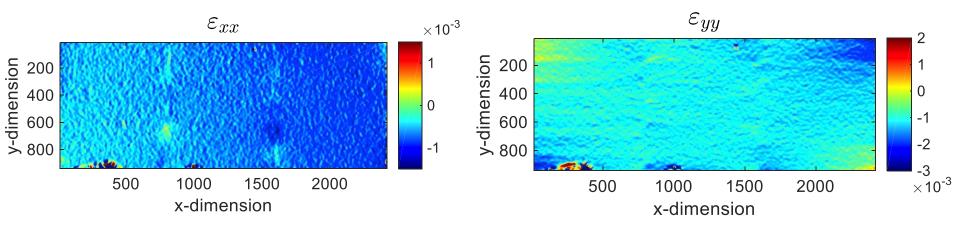
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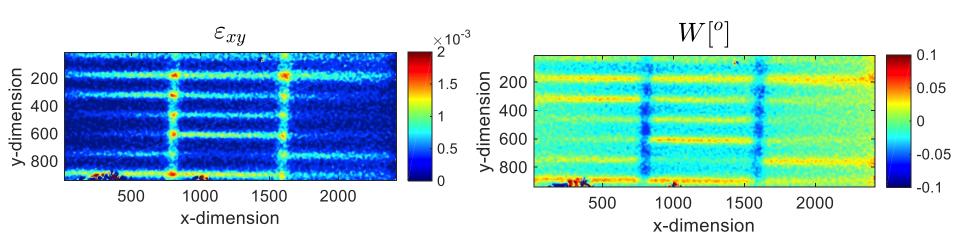


Displacement maps at Point P₁

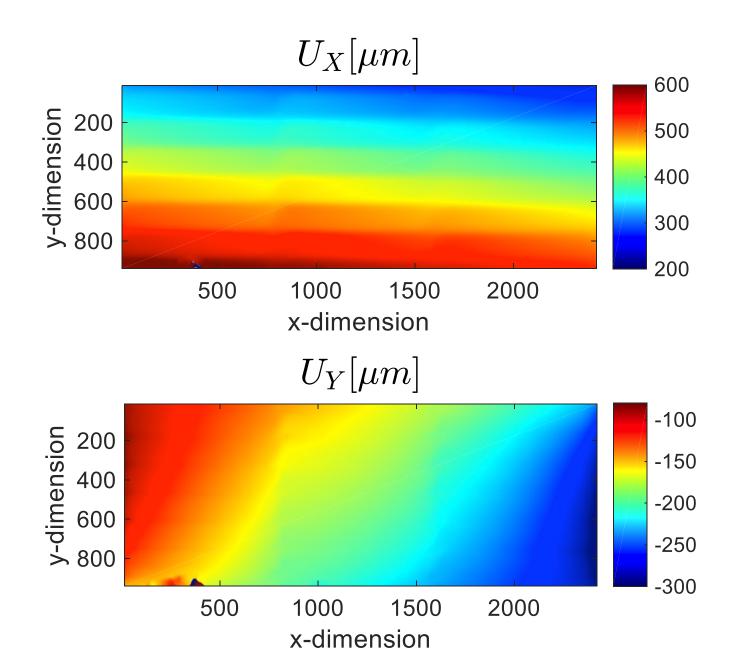


Strain and rotation maps at Point P₁

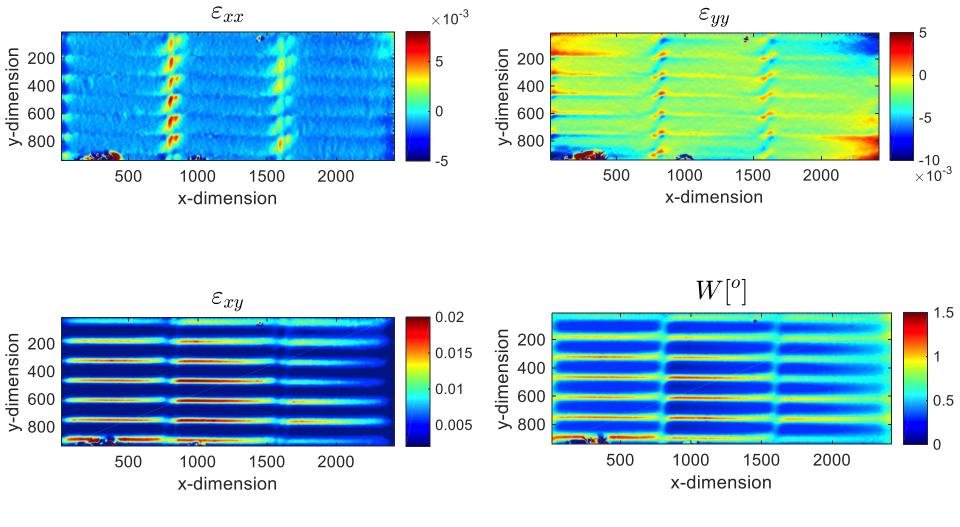




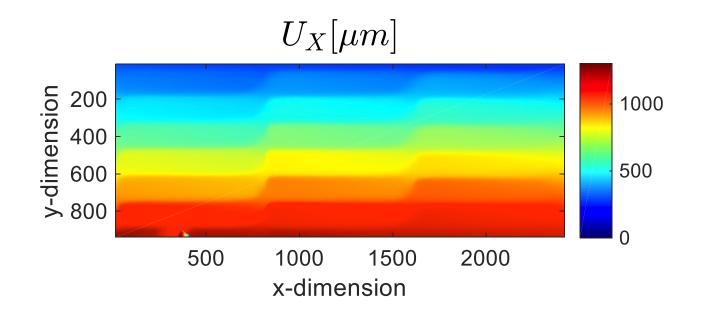
Displacement maps at Points P₂

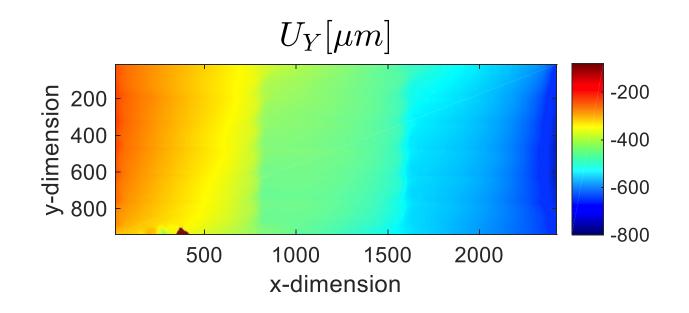


Strain and rotation maps at Point P₂



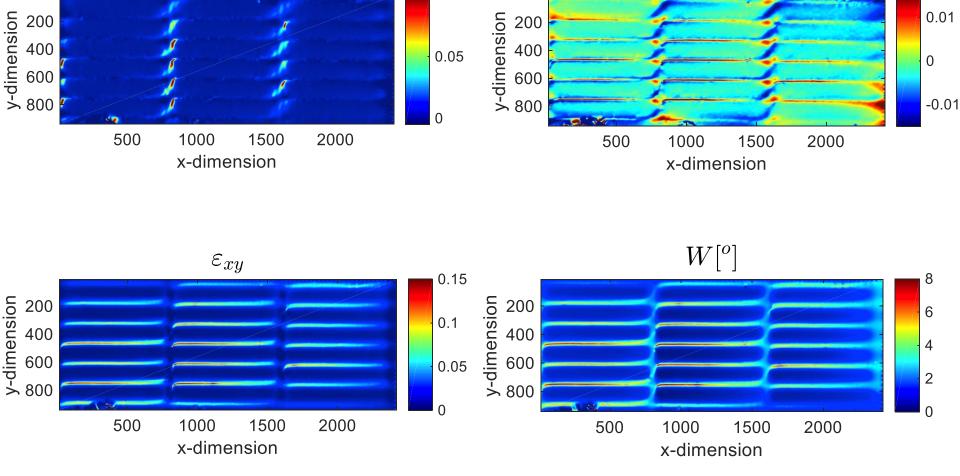
Displacement maps at Points P₃





Strain and rotation maps at Point P₃

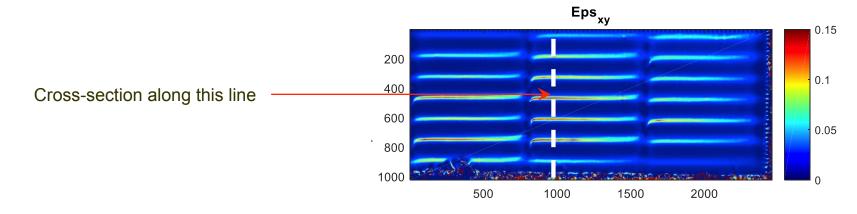
 ε_{xx}



0.1

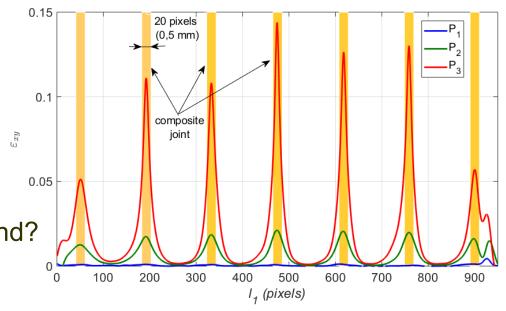
 $arepsilon_{yy}$

Strain field: cross-section of the ϵ_{xy} map for various loading amplitudes



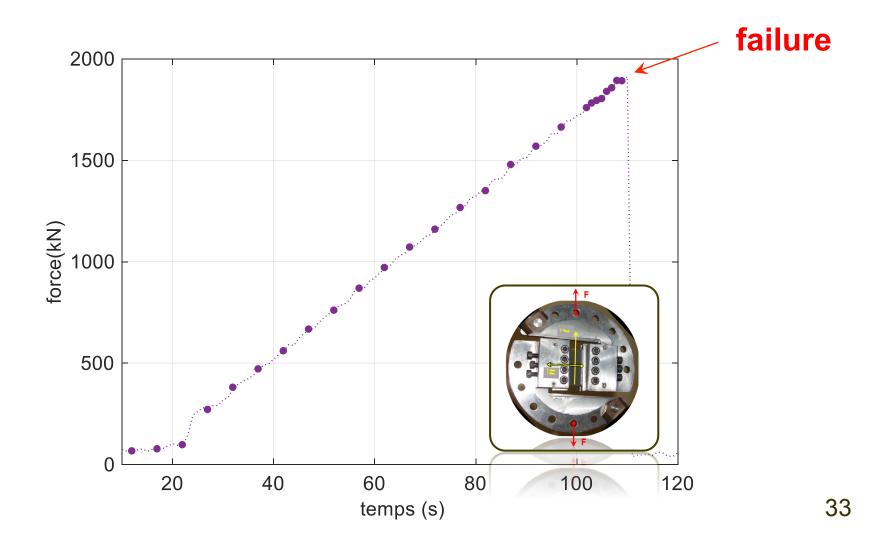
Remarks:

- peaks a sthe load
- smooth distribution...
- ... but blur = systematic error
- actual value within these narrow band?
- systematic error removed up to a certain frequency [1]

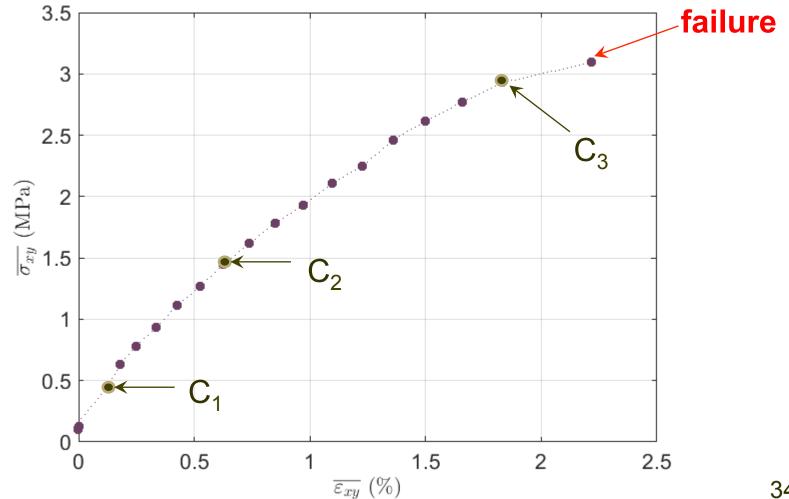


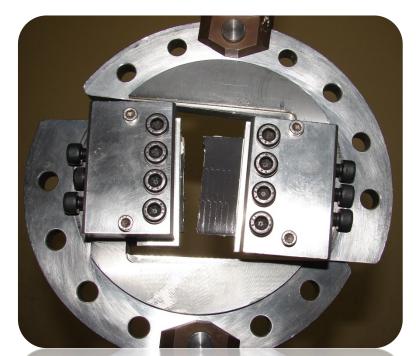
Test B: shear

- force driven 0,02 kN/s, Fmax=1,9 kN
- frequency: 2 images/s
- lighting issues → noiser strain maps

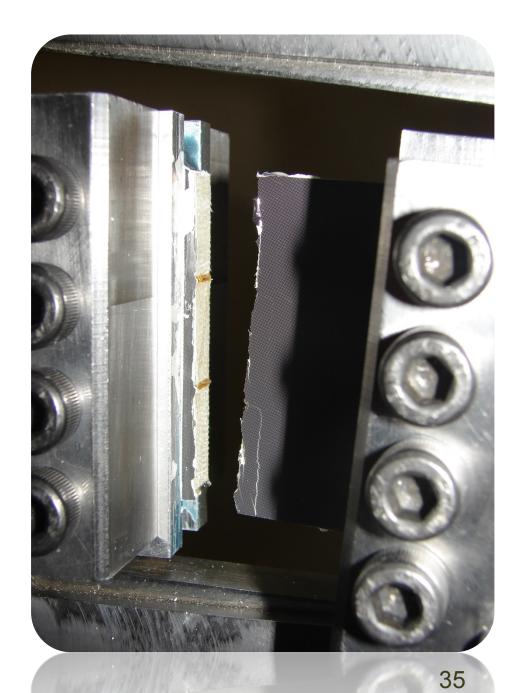


$$\overline{\sigma_{xy}} = \frac{F}{S} \qquad \overline{\varepsilon_{xy}} = \frac{\overline{u_x}(Z_1) - \overline{u_x}(Z_2)}{distance(Z_1, Z_2)}$$

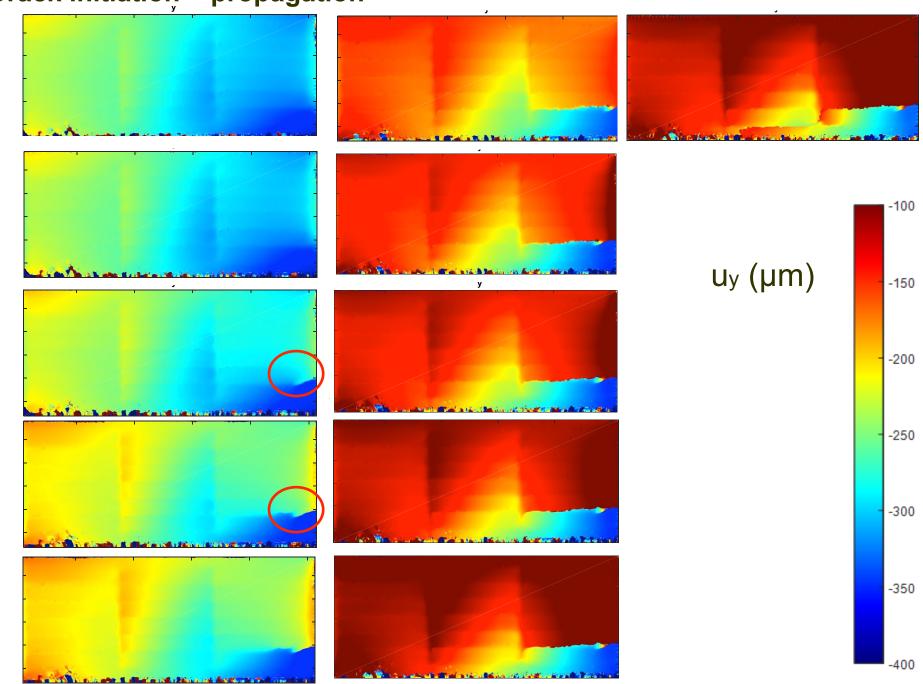








Crack initiation + propagation



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Conclusion:

- feasibility study, in-plane displacement/strain measurement with the grid method
- strong heterogeneities in the strain field due to the heterogeneous nature of the materials
- crack detection (appearance + propagation) in the displacement field

Conclusion:

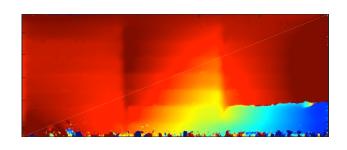
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- information potentially valuable for the design of superconducting magnets

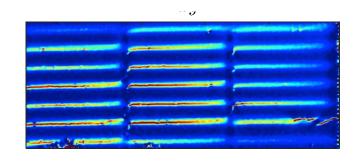
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- crack detection (appearance + propagation) in the displacement field
- information potentially valuable for the design of superconducting magnets
- qualitative or quantitative measurement? → two recent improvements:
 - 1- decreasing the noise level in the map → optimizing the pattern

2- strain maps blurred because of convolution → systematic error → deconvolution algorithm suitable for strain maps [2]

[1] M. Grédiac, B. Blaysat, F. Sur, *Experimental Mechanics*, in press, 2018 [2] M. Grédiac, B. Blaysat, F. Sur, *Experimental Mechanics*, in revision, 2018

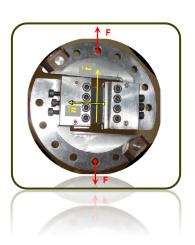


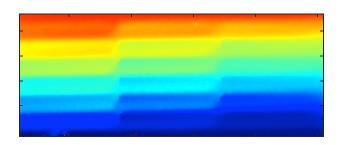


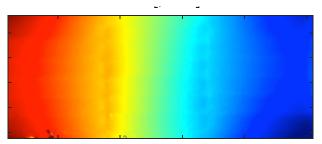


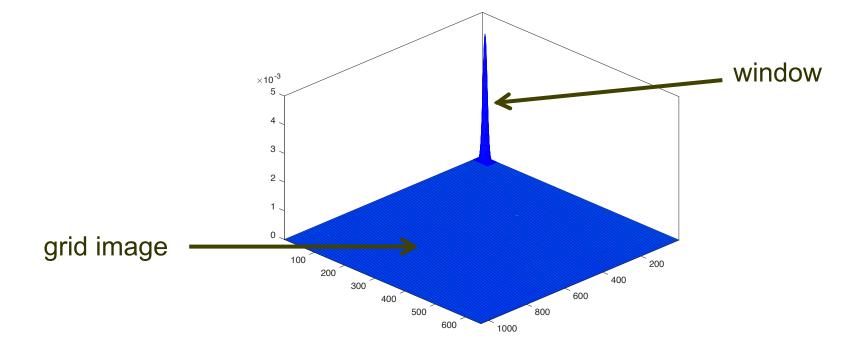
Thank you for your attention

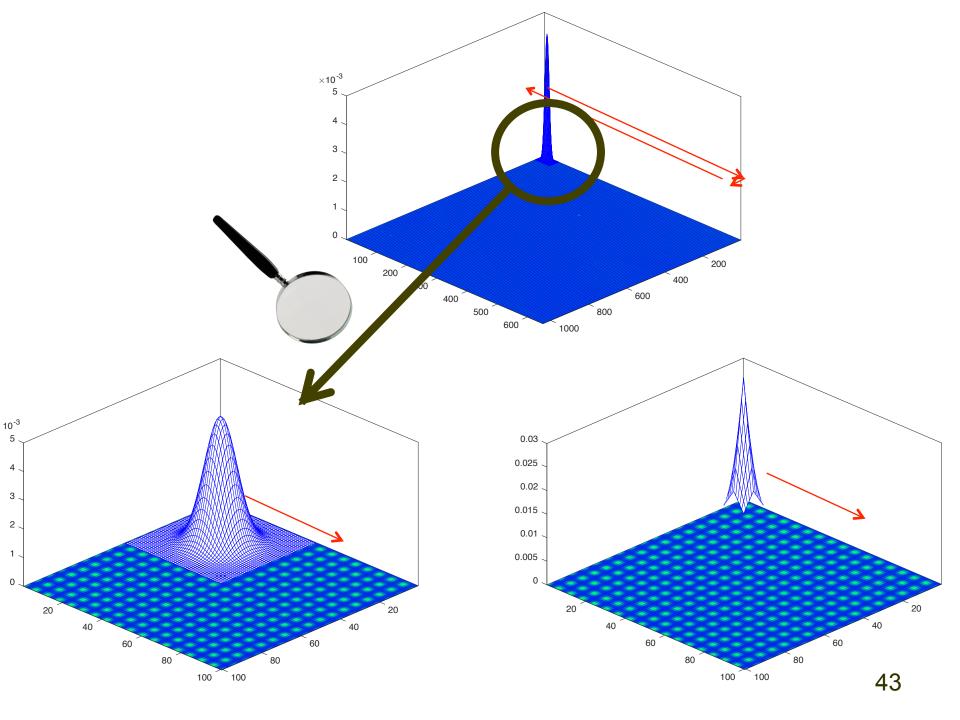
Any questions?





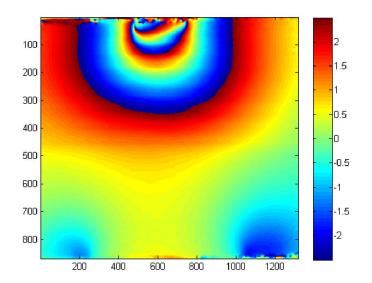




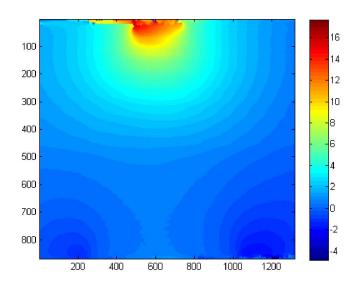


Phase unwrapping:

- argument of a complex number $\to 2\pi$ phase jumps in phase maps if the amplitude of the phase > 2π
- map of « wrapped » phases → phase maps must be « unwrapped » [1]
- example



before unwrapping



after unwrapping

44

• $\widehat{s}(x,y,0,f,\alpha)$ and $\widehat{s}(x,y,f,0,\alpha)$: two complex numbers for each image \rightarrow 2 arguments \rightarrow 2 phases for each image \rightarrow 2 displacement components

$$u_x(x,y) = -\frac{p}{2\pi} \Delta \Phi_x$$
$$u_y(x,y) = -\frac{p}{2\pi} \Delta \Phi_y$$

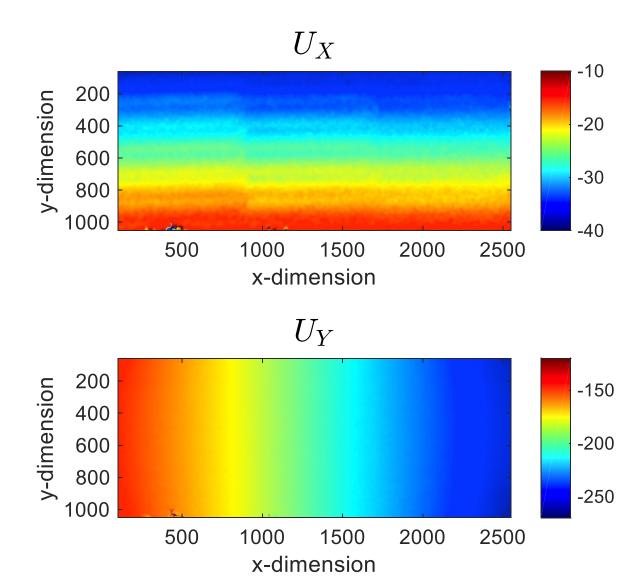
fixed-point algorithm to find the displacement:

$$u_{x}(x,y) = -\frac{p}{2\pi} \left[\Phi_{x}^{cur}(x + u_{x}(x,y), y + u_{y}(x,y)) - \Phi_{x}^{ref}(x,y) \right]$$

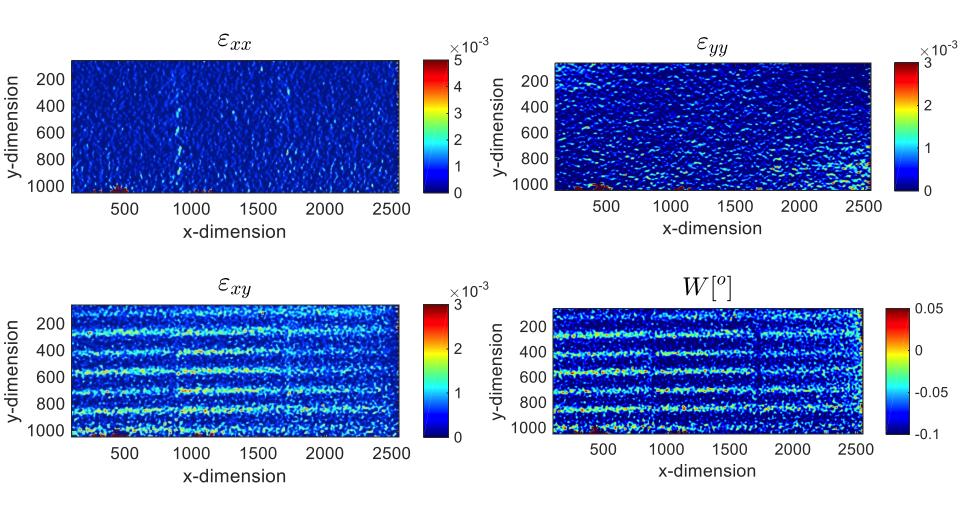
$$u_{y}(x,y) = -\frac{p}{2\pi} \left[\Phi_{y}^{cur}(x + u_{x}(x,y), y + u_{y}(x,y)) - \Phi_{y}^{ref}(x,y) \right]$$

• with small strains, one iteration to reach convergence

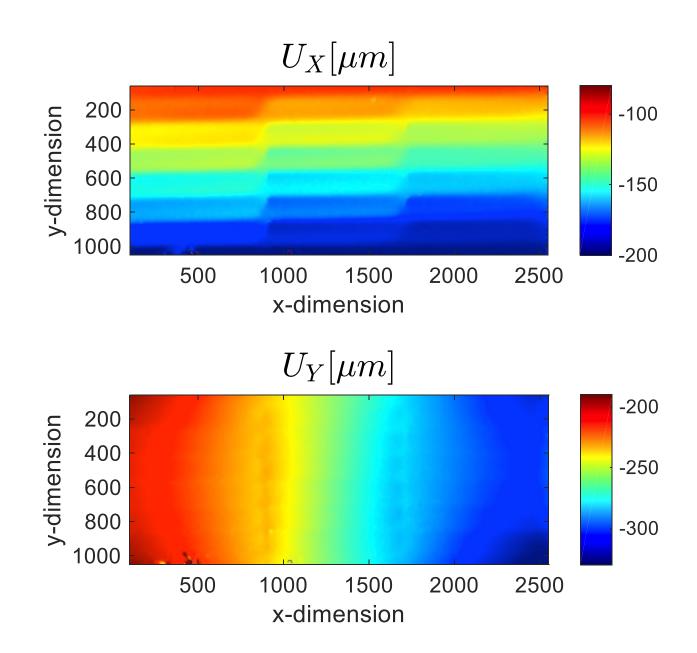
Displacement field at Point C₁



Strain + rotation fields at Point C₁

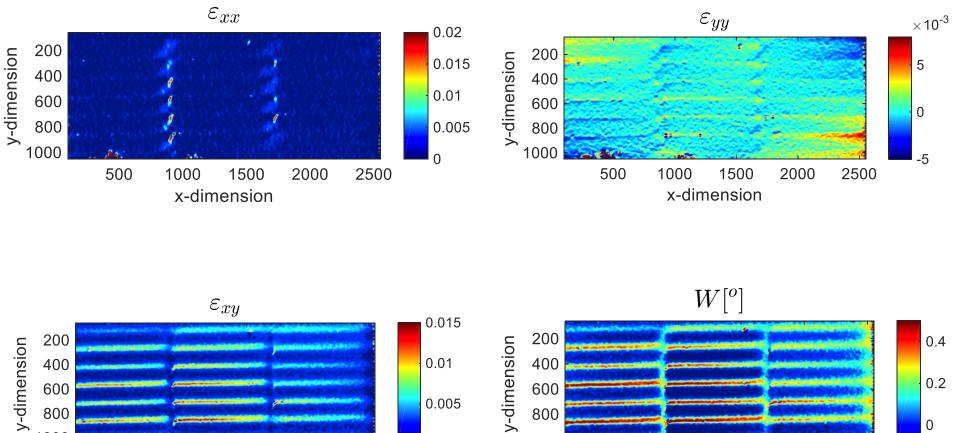


Displacement field at Point C₂



Strain + rotation fields at Point C₂

x-dimension



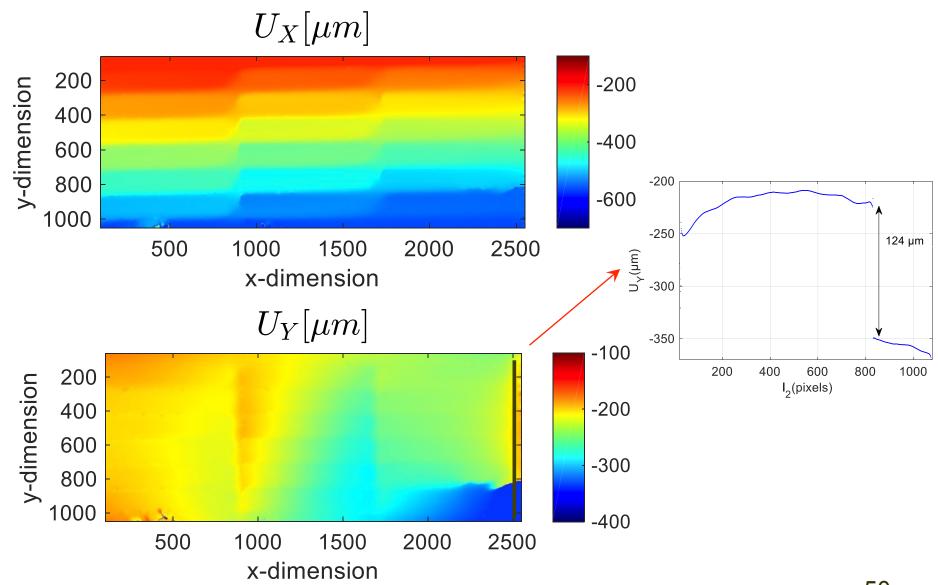
0.01

0.005

x-dimension

0.2

Displacement field at Point C₃



50

Strain + rotation fields at Point C₃

